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# Conflict Minerals in the Compute Sector: Estimating Extent of Tin, Tantalum, Tungsten, and Gold Use in ICT Products

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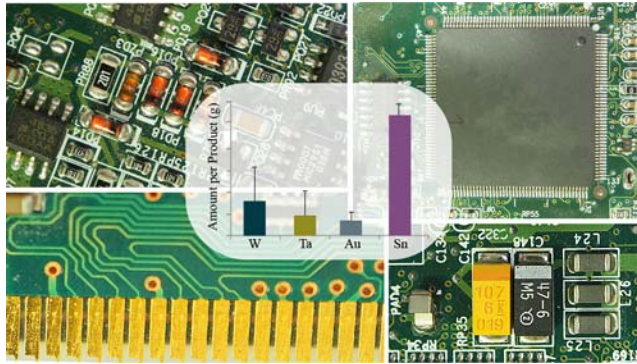
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# TOC ART



## 1 ABSTRACT

2 Recent legislation has focused attention on the supply chains of tin, tungsten, tantalum and gold  
3 (3TG), specifically those originating from the eastern part of the Democratic Republic of Congo.  
4 The unique properties of these so-called “conflict minerals” lead to their use in many products,  
5 ranging from medical devices to industrial cutting tools. This paper calculates per product use of  
6 3TG in several information, communication, and technology (ICT) products such as desktops,  
7 servers, laptops, smart phones and tablets. By scaling up individual product estimates to global  
8 shipment figures, this work estimates the influence of the ICT sector on 3TG mining in covered  
9 countries. The model estimates the upper bound of tin, tungsten, tantalum and gold use within  
10 ICT products to be 2%, 0.1%, 15% and 3% of the 2013 market share, respectively. This result is  
11 projected into the future (2018) based on the anticipated increase in ICT device production.

## 12 INTRODUCTION

13 Throughout history, natural resources have often played a role in conflict. That role has come  
14 under increasing scrutiny over the last two decades when natural resources have provided the  
15 revenues to fuel conflict in developing countries.<sup>1</sup> Although media attention has frequently  
16 focused on the role of drugs, oil, and diamonds, a broader array of resources can play a role in  
17 funding conflict. In response to public concern, a number of schemes have emerged to create  
18 economic disincentives for the use of conflict-related resources; however, the effectiveness of  
19 such market-based schemes depends on significant market participation. To better understand  
20 this potential effectiveness, this paper describes and applies a method to estimate the flow of  
21 “conflict minerals” within the information, communication and technology (ICT) sector.

22 Within the broader context of conflict resources, the term “conflict minerals” has developed a  
23 narrow formal definition (see note at end of document). Specifically, the term conflict minerals is  
24 used to describe minerals that originate from the Democratic Republic of Congo (DRC) or  
25 adjoining states that are processed into tin, tungsten, tantalum and gold (3TG) and associated  
26 with financing severe, ongoing civil conflict in the region.<sup>2, 3</sup> These conflicts lie in mineral rich  
27 areas and are perpetuated by poverty, corruption, land right disputes, regional tensions and  
28 revenues from mining.<sup>4-6</sup> In 2001, a United Nations panel reported on the connection between the  
29 exploitation of mineral resources and armed conflicts in the region.<sup>7</sup> More recently, Non-

30 Governmental Organizations (NGOs) linked the demand for conflict minerals specifically to  
31 consumer goods such as electronics.<sup>8-10</sup> In 2010, the Dodd-Frank Act was adopted requiring  
32 companies that report to the United States Securities and Exchange Commission (SEC) to  
33 disclose their use of conflict minerals in products.<sup>11</sup> However, a number of sources have claimed  
34 that the Act has become a *de facto* ban, reducing economic activity and affecting the livelihoods  
35 of 1 to 2 million artisan miners in the conflict regions as a result.<sup>12-15</sup> A subsequent review of the  
36 impact of Dodd-Frank found that it has significantly reduced the involvement of armed groups in  
37 the production of tin, tungsten and tantalum.<sup>16</sup>

38 Operationally, manufacturers curtail use either by substituting to other materials or by  
39 minimizing the amount acquired in affected regions. Efforts to realize the latter generally support  
40 one of two goals: 1) unambiguously identifying the source of a mineral (auditing) or 2)  
41 increasing the number of (or at least clearly identifying) those sources that do not support  
42 conflict (market segmentation). Significant efforts have emerged to establish certifiable auditing  
43 processes to provide assurances on the sources of minerals used.<sup>17-20</sup> To support those processes,  
44 the German Federal Institute for Geosciences and Natural Resources has initiated pilot projects  
45 to develop certified trading chains and to enhance traceability of the minerals through methods  
46 that map characteristic features of the ore to samples of known origin.<sup>21</sup> In the US, the ICT  
47 industry responded in 2008 with the Conflict Free Smelter Program (CFSP), which is now part of  
48 a broader industry initiative called the Conflict-Free Sourcing Initiative.<sup>22, 23</sup>

49 Consumer electronics, particularly the cell phone, have been highlighted as connected to the  
50 demand for these minerals from within the conflict areas of the DRC.<sup>4, 6</sup> Therefore, this work  
51 explores global production of conflict minerals linked to the ICT industry to understand the  
52 ability of this sector to send an economic signal to smelters and refiners. To achieve this goal,  
53 we estimate and assess the quantity of these metals contained within a subset of consumer  
54 electronic products including smart phones, tablets, notebooks and desktop computers, servers  
55 and displays. This work develops **upper-bound** assessments of per product use of 3TG. Per  
56 product use is then scaled with data for global sales and production of equipment, including  
57 projections of future product sales. Upper-bound estimates capture a conservative approximation  
58 of 3TG content given the wide variation across ICT products and the significant challenges in  
59 tracing the quantities of these materials purchased by ICT brand companies. As many as nine  
60 tiers separate the miners and smelters from the final manufacturers, which is often still not the  
61 original equipment manufacturer (OEM).<sup>24</sup> Generally a supplier loses visibility beyond the first  
62 few tiers, as the quantity of suppliers explodes exponentially (EICC & D. Martin, e-mail  
63 communication, July 2014). Previous studies have commented on the challenge of estimating  
64 materials content due to lack of data.<sup>25</sup>

65 Previous work to quantify materials use in electronics has done so for several primary reasons,  
66 including 1) environmental evaluation through life cycle assessment (LCA), 2) assessment of  
67 toxicity potential, 3) determination of value of materials recovery for waste management, 4)  
68 understanding the overall flows of materials through society through materials flow analysis  
69 (MFA), or combinations of the above. In the case of LCA, a few studies have reported quantities  
70 for a subset of 3TG either at the component or whole product level. These are often based on  
71 visual assessment of disassembly data and may be drawn from just a few product tear downs.<sup>26-29</sup>  
72 For example, in the work of Deng *et al.*, authors report a number for gold based on a study from  
73 1998 and tin based on a study from 2007.<sup>27</sup> For toxicity potential or materials recovery, materials

74 of value or perceived toxicity, such as gold and tin, are quantified through leaching treatments.<sup>30-</sup>  
75 <sup>34</sup> For MFA, end use sectors are used to estimate the amount of material produced, fabricated,  
76 used and disposed of across particularly geographic regions over particular time scales.<sup>35-37</sup> In the  
77 case of 3TG, materials flows have been characterized for tungsten<sup>38</sup> and tin<sup>39</sup>; however, these  
78 examples do not emphasize the electronics end use, thus do not provide estimates to compare to  
79 the work presented here. A recent study has quantified the amount of copper, gold, palladium,  
80 silver, nickel, lead, antimony and tin to determine the energy consumed to recover metals from  
81 mobile phones.<sup>40</sup> Extensions of MFA based on input-output models (WIO-MFA) have also been  
82 developed to estimate flows of substances within commodities, with particular emphasis on  
83 trade.<sup>41, 42</sup> The current contribution provides a way of estimating metal content not previously  
84 undertaken for these materials within these product categories. A recent review article on a  
85 related topic has commented on the lack of such bottom up approaches based on product  
86 attributes, such as area of components or pin count.<sup>43</sup>

87 First, this paper describes the current supply status and application for each of the metals. Then  
88 the paper describes the method for estimation of per product concentration and scales this  
89 estimate according to total global shipments.

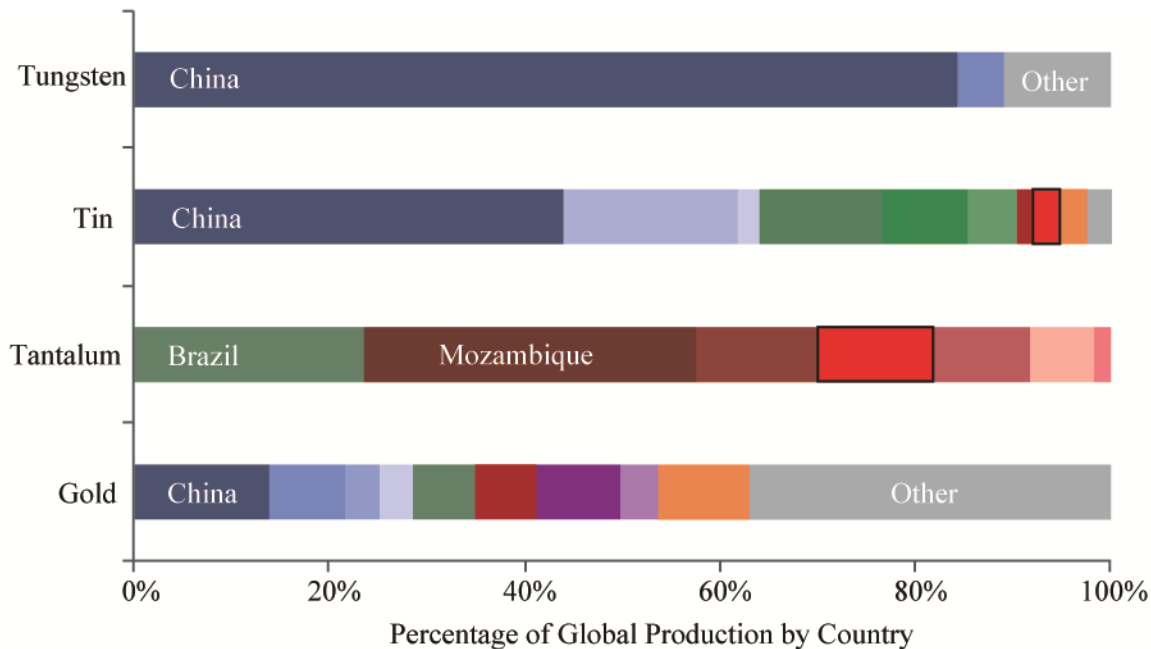
## 90 MATERIALS OVERVIEW

91 This section provides an overview of each of the focus materials. The primary uses of **tungsten**  
92 include cemented carbides, mill products, steels alloys, and chemicals.<sup>44, 45</sup> Tungsten's favorable  
93 combination of properties (e.g., high melting point, low coefficient of expansion, and high  
94 hardness) limits options for substitution, especially cost effective substitutions where  
95 performance at high temperatures is desired. As shown in Figure 1, China dominates world  
96 production of tungsten, accounting for over 84 percent of the roughly 73,000 tons of tungsten  
97 produced worldwide in 2011.<sup>46</sup> Canada and Russia account for roughly 8 percent of the  
98 worldwide production, or half of the remaining production that is not from China.<sup>46</sup>

99 Corrosion resistance, ductility and durability make **tin** a favorable choice for alloying with other  
100 metals and for coating harder metals (e.g. with steel to form tin cans or tinplate). The primary  
101 uses of tin include solders, tinplate, chemicals, brass, and float glass.<sup>47-49</sup> Solder is the application  
102 relevant to the ICT industry, but solder is used extensively in all electrical and electronic  
103 products. Tin solders generally have tin concentrations between 5% and 98% by weight, and the  
104 greater the tin concentration, the greater the solder's tensile and sheer strengths. Unlike  
105 tungsten, there are substitutions for tin including epoxy resins for tin solder, and aluminum  
106 alloys, copper-based alloys, and plastics for tin bronze.<sup>50</sup> Roughly 60% of the global mine output  
107 comes from China and Indonesia, with China leading with close to 50% of global mine output  
108 and 30% of global reserves.<sup>47</sup>

109 **Tantalum** is a refractory metal that is ductile, easily fabricated, highly resistant to corrosion by  
110 acids, a good conductor of heat and electricity, as well as possessing a high melting point. The  
111 primary uses of tantalum are capacitors (the relevant end use for electronic products), mill  
112 products, chemicals, sputtering targets, powders, and carbides.<sup>51, 52</sup> Tantalum became desirable in  
113 electronics based on the discovery of directional conductivity in tantalum oxide leading to the  
114 development of the tantalum capacitor. Brazil and Mozambique have been the leading tantalum  
115 producers, followed by Rwanda and DRC.<sup>53</sup>

116 **Gold** is the most malleable of metals; it is unaffected by air, moisture, and most corrosive  
 117 reagents, making it a good protective coating on more reactive metals. The primary uses of gold  
 118 include jewelry, electronics, and bars and coins.<sup>54</sup> The top 10 gold producing countries are  
 119 responsible for two-thirds of global gold production, yet no one country produces more than 14%  
 120 of the global production as demonstrated by the multitude of bars in Figure 1.<sup>55, 56</sup> China  
 121 currently leads global production and consumption, followed by Australia and the United States  
 122 on the production side, and India and the United States on the consumption side. Gold  
 123 originating from the conflict countries is a small minority of the volume, less than 1%, and the  
 124 large scale of miners and refiners have contributed to responsible sourcing.<sup>54</sup>



125  
 126 **Figure 1. Percentage of production for tungsten, tin, tantalum, and gold by country for the top producing countries.**<sup>46, 49,</sup>  
 127 <sup>53, 54</sup> Regions are grouped by color: Asia (blue), South America (green), Africa (red), North America (purple), Oceania  
 128 (orange), and Other (grey). The two red bars outlined with black shown in tin and tantalum are for the covered countries:  
 129 the DRC and Rwanda, respectively.

130 **METHOD**

131 To establish the percentage of global consumption of conflict minerals attributable to typical  
 132 consumer electronics, we estimated the material per component (or attribute), which was then  
 133 scaled with the number of such components per product. The model used to estimate content was  
 134 a mechanistic, physical model rather than an empirical model due to limited product-specific  
 135 data availability and the challenge with measuring metal content directly. We focused on  
 136 attributes that were reported in product teardown reports.

137 Each model establishing the quantities of conflict minerals relies on comprehensive product  
 138 teardown reports of the products in question. These reports provide complete details of all of the  
 139 electronic, electromechanical, and mechanical components employed in a product. Tear down  
 140 data were used from several industry sources as well as third party companies.<sup>57</sup> Emphasis was  
 141 placed on more recent models with at least one, if not all, of the tear downs from products made  
 142 from 2011 onwards. Because of the expense of obtaining these reports and their selective

143 availability, two tear downs per product type were used in most cases, with the exception of  
144 tablets, where 25 tear down reports were available. Wherever possible, more commonly sold  
145 products within a category were used for the estimation. Given the large range of configurations  
146 of electronic products, significant uncertainty exists in these estimates. Uncertainty was  
147 estimated by generating a range in metal content per attribute for each conflict mineral based on  
148 the data within the 25 tablet reports. This range was increased by 50% to provide uncertainty  
149 range for the products where more tear down reports were not available. Also, as described for  
150 each material below, upper bound assumptions were made to deliberately overestimate the  
151 conflict minerals content within ICT, including scrap loss in production. A summary of the  
152 relevant detail provided is shown in the supporting information and described below. The  
153 mechanistic models for each material are described below in text and equation form. The  
154 supporting information also provides example images of the components of interest.

155 The modeled ‘per product’ figure was then scaled by global sales data to estimate global usage  
156 by this product group.<sup>58-61</sup> Finally, this number was represented as a percentage of global  
157 production for each metal. The accuracy of these estimates has been gauged based on their  
158 congruence with related estimates, where possible, and through interviews with relevant  
159 materials-based industry associations.

## 160 TUNGSTEN ESTIMATE

161 The following paragraphs describe the assumptions used to develop the mechanistic, physical  
162 model for tungsten content in ICT products. Tungsten has two primary uses in consumer  
163 electronics, smart phone vibration motors (a small electric motor used to notify the user of an  
164 incoming connection) and vias (opening in an oxide layer that allows conductive connection  
165 between layers) in integrated circuits (ICs). Due to its high density, tungsten enclosed in the  
166 vibration motor of a cell phone enables large vibration within a small form factor.<sup>45</sup> For IC vias,  
167 tungsten is deposited between the metal tracks used to connect components. Tungsten’s  
168 conductivity, thermal expansion properties and suitability for chemical vapor deposition  
169 promotes its use in IC vias.<sup>62</sup>

170 The quantity of tungsten in a typical vibration motor was found by removing the tungsten piece  
171 from a number of typical motors in smart phones, weighing them directly and calculating the  
172 average figure. This was determined to be 1 g, though industry feedback we received indicated a  
173 tungsten-heavy alloy is used with weight slightly higher than 1 g.

174 The estimates for tungsten used in ICs were calculated for the quantity of tungsten deposited  
175 during the fabrication of the vias, much of which is lost during chemical and mechanical  
176 polishing. As such, the calculated figures for tungsten include not only the tungsten present in  
177 the product but also tungsten that is consumed during fabrication.

178 The quantity of tungsten consumed for an IC is related to the number of metal layers that must be  
179 connected,  $L$ , the volume of the tungsten layer that is deposited,  $R_H * T_L * A$ , the process yield,  $S$ ,  
180 and the density of tungsten,  $\rho_w$ . The data from the teardown reports only supplied the packaged  
181 IC area,  $A$ , thus several assumptions were necessary. The IC die area (the area of the silicon chip  
182 itself) was estimated from the package dimensions and an upper bound die to package area ratio,  
183  $R_H$ , of 0.8:1. This ratio is based on an upper bound of previously reported and measured  
184 figures.<sup>63</sup> The other main assumptions were that all ICs contained eight metal layers ( $L$ ), and that  
185 layer thickness,  $T_L$ , equaled  $0.5\mu\text{m}$ , (based on multiplying an assumed a via size of  $0.08\ \mu\text{m}$  by

186 an assumed aspect ratio of 6.2 in line with the current generation of technology).<sup>64</sup> A safety  
 187 factor,  $S$ , of three was added to account for the metal yield of the chemical vapor deposition  
 188 process used to deposit tungsten on the IC. Equation 1 shows the physical description underlying  
 189 the model and the equation used.

	Tungsten in vibration motor	Tungsten in ICs
Physical description	Quantity * Weight	Number of metal layers * Volume of tungsten layers * Tungsten density
Equation	$W (g) = (N * w) + (L * R_H * T_L * S * \rho_W) \sum_{n=1}^x A_n \quad Eqn. 1$	

190 Where  $N$  is the number of vibration motors,  $w$  is the weight of tungsten in a motor (in g),  $L$  is the  
 191 number of layers,  $R_H$  is the ratio of die area to package area,  $T_L$  is the layer thickness (in mm),  $S$   
 192 is the process yield,  $\rho_W$  is the density of tungsten (in  $g/mm^3$ ),  $x$  is the number of ICs, and  $A$  is the  
 193 IC package area (in  $mm^2$ ). The latter part of this calculation was summed for all ICs to achieve a  
 194 total for the tungsten due to ICs in the product.

## 195 TIN

196 The dominant use of tin in electronics is solder, providing a mechanical and electrical connection  
 197 between components and the printed circuit board. The vast majority of components used in  
 198 consumer electronics are surface mounted, which are soldered used a technique known as reflow  
 199 soldering. Tin is also present in Indium Tin Oxide (ITO), used as an electrode on flat panel  
 200 displays. We found this latter application to be trivial in magnitude compared to that of solder,  
 201 thus we focused solely on solder in the physical model for tin.

202 The quantity of tin was estimated from the volume of solder paste applied,  $T_S * A_C$ , the tin  
 203 content of that paste,  $\zeta$ , and the paste density,  $\rho_{Sn}$ . The volume of the solder paste was computed  
 204 as the product of the surface area of the footprint (or land pattern),  $A_C$ , of the components to be  
 205 soldered and the thickness of the stencil employed,  $T_S$ . The land pattern is the outline of the pads  
 206 that a component will be soldered on. The stencil is the patterned template for the metal  
 207 deposition on a printed circuit board and an image is shown in the supporting information. The  
 208 stencil thickness is the same as the solder paste height and so serves as a reasonable proxy to  
 209 estimate solder thickness. The area for each component was available from component  
 210 datasheets (specific to each type of component) and the thickness of the stencil,  $T_S$ , was chosen  
 211 as 0.16 mm, a high estimate, based on the fine pitch nature of the components used.<sup>65</sup> The values  
 212 for solder paste density,  $\rho_{Sn}$ , and tin content,  $\zeta$ , by volume were taken from a typical solder paste  
 213 data sheet. This is expressed in equation 2.

## Tin in solder

Physical description	Volume of solder applied per component * Solder tin content * Tin density
----------------------	---



Equation 
$$Sn(g) = (T_S * \zeta * \rho_{Sn}) \sum_{n=1}^c A_{cn} \quad Eqn. 2$$

214

215 Where  $T_S$  is the stencil thickness (in mm),  $\zeta$  is the tin content of the solder paste,  $\rho_{Sn}$  is the  
 216 density of tin (in g/mm<sup>3</sup>),  $A_c$  is the area of the component land pattern (in mm<sup>2</sup>), and  $c$  is the  
 217 number of components. This calculation was repeated for every component to achieve a total  
 218 quantity for the tin.

219 TANTALUM

220 In electronics, tantalum has two main applications. Firstly, it is used in the production of certain  
 221 capacitors due to its volumetric efficiency and reliability.<sup>66</sup> Volumetric efficiency,  $E$ , is increased  
 222 by creating tantalum powders with very high surface area per unit of mass. A measure of the  
 223 volumetric efficiency is CV/g describing the product of the capacitance (C in  $\mu$ F) and the voltage  
 224 (V) that is possible per gram of material (g). Capacitance and voltage are either included directly  
 225 in product teardowns or can be deduced from form factors provided, in addition to the capacitor  
 226 dimensions.

227 The volumetric efficiency of capacitor grade tantalum powders has increased from about 2,000  
 228 CV/g to over 100,000 CV/g making capacitors with small footprints possible.<sup>52</sup> A value,  $E$ , of  
 229 52,750 CV/g was used, representing the weighted average volumetric efficiency of capacitor  
 230 grade tantalum powder sales across the industry (Tantalum and Niobium Center, email  
 231 communication, February 2014). To determine the quantity of tantalum in the wire, a  
 232 relationship between the length,  $l_i$ , and diameter,  $w_i$ , of the wire was made based on published  
 233 cross sections and schematic diagrams. Tantalum wire was determined to be approximately 0.5  
 234 the length of the capacitor package ( $f_l$ ) and the diameter is approximately 0.15 of its width, ( $f_w$ ).<sup>66</sup>

235 Thus, knowing the voltage rating, capacitance and dimensions of each tantalum capacitor used in  
 236 a product in conjunction with the volumetric efficiency of current tantalum powders enabled the  
 237 calculation of the quantity of tantalum used as shown in equation 3.

Tantalum in capacitors

Physical description	Relative volumetric efficiency	wire volume * tantalum density
----------------------	--------------------------------	--------------------------------

Equation 
$$Ta_{caps}(g) = \sum_{n=1}^t \frac{C_{tn} * V_{tn}}{E} + \pi * \rho_{Ta} (f_w * w_{tn})^2 * (f_l * l_{tn})$$

Eqn. 3

238 where  $t$  is the total number of tantalum capacitors,  $C_i$  is the capacitance (in  $\mu$ F),  $V_i$  is the voltage  
 239 rating (in V),  $E$  is the volumetric efficiency of the tantalum powder used (in  $\mu$ FV/g),  $w_i$  is the  
 240 width of each capacitor (in mm),  $f_w$  is the fraction of that width that is wire,  $l_i$  is the length of  
 241 each capacitor (in mm),  $f_l$  is the fraction of that length that is wire, and  $\rho_{Ta}$  is the density of  
 242 tantalum (in g/mm<sup>3</sup>). This calculation was repeated for every tantalum capacitor in the product to  
 243 find the total.

244  
 245 The second application of tantalum in electronics is as thin film Ta(Si)N barrier layers for  
 246 preventing interdiffusion in ICs with copper interconnects.<sup>62</sup>

247 The quantity of tantalum used in IC fabrication is related to the number of metal layers,  $L$ , which  
 248 must be connected, the area of the die,  $A$ , and the thickness of the barrier layer,  $R_H * T_F$ . The  
 249 teardown reports supplied the IC package dimensions, requiring a number of assumptions to  
 250 estimate tantalum quantity. The main assumptions were that all of the ICs have eight metal layers  
 251 and the die to package relationship is 0.8:1, as stated previously.<sup>6</sup> Also, a layer thickness,  $T_F$ , of  
 252 65 nm has been assumed based on industry data that reports the Ta use in sputtering targets is  
 253 approximately one third of that employed in capacitor grade powders and wire.<sup>67</sup> These terms are  
 254 combined in equation 4.

#### Tantalum in ICs

---

Physical description                      Number of metal layers \* Volume of layers \* Tantalum density

Equation                                       $Ta_{film} = (R_H * L * T_F * \rho_{Ta}) \sum_{n=1}^x A_n$                                       Eqn. 4

255 Where  $T_F$  is the film layer thickness (in mm),  $\rho_{Ta}$  is the density of tantalum (in g/mm<sup>3</sup>),  $x$  is the  
 256 total number of ICs, and  $A$  is the IC package area (in mm<sup>2</sup>). This was repeated for all ICs to  
 257 achieve a total quantity of tantalum in the IC for the product.

#### 258 GOLD

259 Gold's desirability in electronics is due to a combination of its conductance, malleability and  
 260 corrosion resistance. It is used extensively to create durable, consistently-conductive connections  
 261 for card-to-board interfaces. Gold wire is also used to bond silicon die pads to IC package leads.  
 262 Currently a trend to substitute copper for gold is underway due to copper's lower cost, superior  
 263 conductivity and recent advances in manufacturing capabilities.<sup>52</sup> Despite this trend, in the spirit  
 264 of generating upper bound estimates, we assume wire bonding is done with gold. In general there  
 265 is a lack of information regarding where in an electronic device, outside of the printed circuit  
 266 board, gold may be found.<sup>68</sup>

267 For the card-to-board interfaces, each gold contact was measured to assign an area,  $A_s$ . To map  
 268 the area to volume we assumed a coating thickness,  $T_s$ , based on market survey data and  
 269 information on contact reliability as a function of the number of expected mating cycles (i.e., the  
 270 number of times components are connected and disconnected). For this estimate, we  
 271 approximated a coating thickness of 0.76  $\mu$ m based on parts requiring a higher number of mating  
 272 cycles (10,000), such as USB ports.<sup>69</sup> With this established volume of gold, the total quantity of  
 273 gold was calculated using its density as shown in equation 5.

#### Gold in connectors

---

Physical description                      Number of contacts \* Volume of contacts \* Gold density

Equation 
$$Au_{connectors} = \rho_{Au} \sum_{n=1}^s N_n * A_{sn} * T_{sn} \quad Eqn. 5$$

274 Where  $s$  is the total number of connectors,  $N$  is the number of contacts per connector,  $A_s$  is the  
 275 area of the contacts (in  $mm^2$ ),  $T_s$  is the thickness of the contacts (in mm) and  $\rho_{Au}$  is the density of  
 276 gold (in  $g/mm^3$ ).

277 The mass of gold in bonding wires is estimated from the number of IC to package  
 278 interconnections required,  $N_I$ , the length of those connections (described below), and the area of  
 279 the wire,  $\pi*(d/2)^2$ . The number of interconnections is estimated directly as the number of IO pins  
 280 reported for the IC in the teardown reports. The length of the wire was estimated based on the  
 281 distance between the outer edge of the die and the IO pins. This gap was calculated by  
 282 subtracting the square root of the chip area, ( $A * R_H$ ) from the length of the die,  $L_I$ , as shown  
 283 below in equation 6. A wire diameter,  $d$ , of  $15\mu m$  is used, typical for the fine pitch chips  
 284 employed in ICT products. This is shown in equation 6.

#### Gold in bonding wire

Physical description Volume of Bonding Wire \* Number of Pins \* Density of Gold

Equation 
$$Au_{wire} = \pi * \left(\frac{d}{2}\right)^2 * \rho_{Au} \sum_{n=1}^x \left[ N_{In} * \left( \frac{L_{In} - \sqrt{A * R_H}}{2} \right) \right] \quad Eqn 6$$

285 Where  $x$  is the total number of ICs,  $d$  is the diameter of the bonding wire (in mm),  $L_I$  is the length  
 286 of the IC (in mm),  $N_I$  is the number of IO pins, and  $\rho_{Au}$  is the density of gold (in  $g/mm^3$ ).

287 Finally, on a printed circuit board, the conductor surface of the landing pad forms the critical  
 288 interface between the components and the board. The primary purpose of the final finish is to  
 289 create a protective coating in order to preserve solderability by preventing oxidation on the  
 290 landing pad that could result in a bad joint. Several different materials and approaches may be  
 291 used to create this final finish, with an estimated 12% of printed circuit boards by surface area  
 292 employing electroless nickel immersion gold (ENIG).<sup>65</sup> However, mobile devices usually do not  
 293 employ ENIG solder joints as they have been demonstrated to be less tolerant of physical shock.  
 294 For this reason, a gold surface finish has only been assumed for the non-mobile products under  
 295 investigation including desktops, servers and displays. For each of these a finish thickness,  $F$ , of  
 296  $0.15 \mu m$  has been assumed at the upper limit of what is advised.<sup>65</sup> The expression is shown in  
 297 equation 7.

298

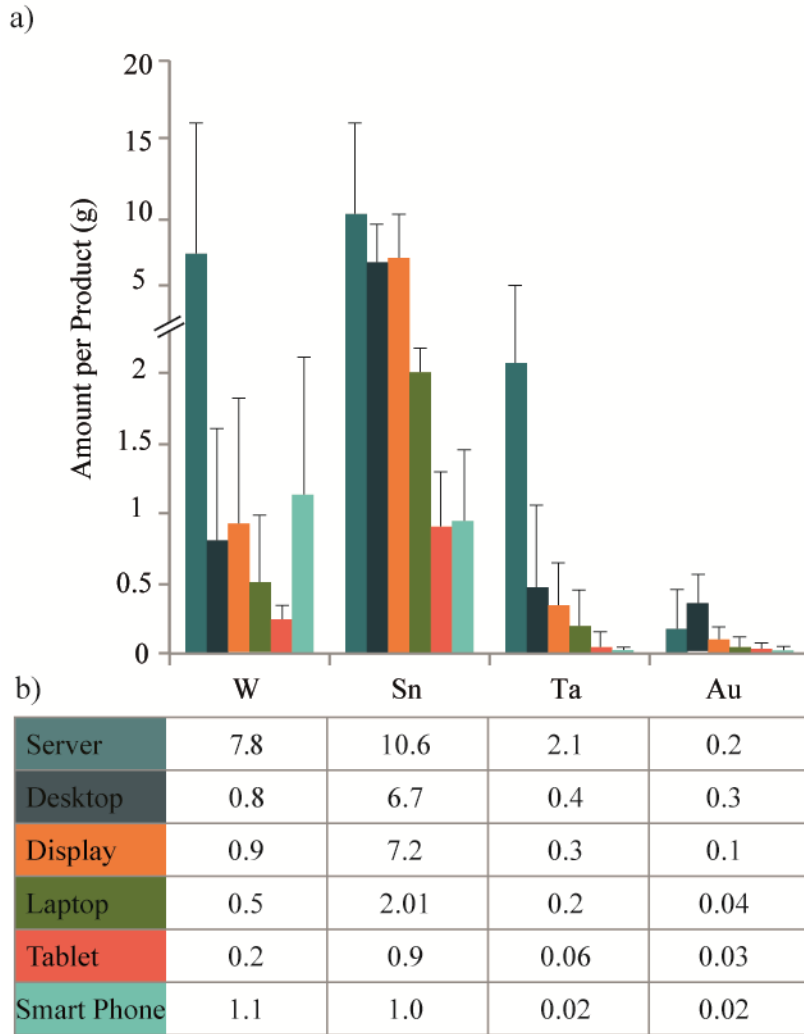
$$Au_{coating} = (\rho_{Au} * F) \sum_{n=1}^c A_{cn} \quad Eqn 7$$

299 Where  $\rho_{Au}$  is the density of gold (in  $g/mm^3$ ),  $F$  is the finish thickness (in  $\mu m$ ),  $c$  is the number of  
 300 components,  $A_c$  is the area of the component land pattern (in  $mm^2$ ).

301 Further consideration was made for the scrap generated for each of these materials as a function  
 302 of their processing conditions. Details of this are provided in the discussion section.

303 **RESULTS**

304 An estimate was made of the per product use by product type for each focal material, essentially  
 305 providing a technology-based content assessment. The result of these estimates, based on an  
 306 average for each of the investigated products examined, is shown in Figure 2. As mentioned  
 307 previously, the aims of the modeling approach were to overestimate the total content of each  
 308 material to achieve a theoretical upper bound of tungsten, tin, tantalum, and gold in ICT.



309  
 310 **Figure 2. Estimated amount of tungsten, tin, tantalum and gold contained in servers, desktops, displays, laptops, tablets**  
 311 **and smart phones a) graphically and b) in table form. The maximum whisker shows one standard deviation above the**  
 312 **mean.**

313 The estimates show that the amount of each of these materials varies by product, as would be  
 314 expected. Tungsten is high in the server relative to the other products, and the levels of tin are  
 315 similar for servers, desktops and displays. Technology forecasting indicates that vibrate  
 316 functions might be added to additional products (such as tablets). This might increase the amount

317 of tungsten in ICT products. While the overall number of tantalum containing capacitors is high  
 318 for mobile products, the amount of tantalum within each capacitor has been decreasing over time  
 319 so this amount may be high for tantalum in the next five years.<sup>58</sup> The ratio of tantalum in the  
 320 capacitor versus film was found to be three to one. The amount of gold estimated by this study in  
 321 mobile products is lower than previous estimates, but on the same order of magnitude (see  
 322 below), possibly reflecting efforts to reduce gold content in these products based on cost. The  
 323 majority of gold was found to be in the connectors as opposed to bond wire or board surface  
 324 finishing.

325 To compare these results with previous analyses we look to the papers mentioned above that  
 326 assess materials content for environmental evaluation, waste recovery value or materials flow.  
 327 The quantities of gold, tantalum, and tin found in a mobile phone has been previously estimated  
 328 at 0.024–0.044 g, 0.1g and 0.625–1 g, respectively, for PCs the amount of gold was 0.2 g.<sup>28, 32, 40</sup>  
 329 These per product estimates are close to what has been estimated using the model presented here.  
 330 The individual product estimates were scaled by global shipments of these products, as shown in  
 331 Table 1. The percentage of the market for each material across all the products investigated is  
 332 also shown based on the total production in 2013 and forecasted production in 2018. For the  
 333 forecasted percentages, the number of displays, tablets, and smart phones is expected to increase  
 334 as well as total number of product shipments. Both factors drive up the market share for 3TG in  
 335 electronics across all of the materials. Metals industry associations for tungsten, tantalum and  
 336 gold estimate the use of these metals in electronics generally to be 1400, 1000, and 270 t/y,  
 337 respectively.<sup>45, 54</sup> Given the different modeling approaches between these estimates and our  
 338 calculation, the numbers are of similar magnitude. In the case of tantalum and gold the numbers  
 339 represent all of electronics, while we quantify a subset of this category.

340 **Table 1. Scaled results for each material within each product category. Scaled by 2013 global shipments. The**  
 341 **forecasted shipments are provided below pulled from the same references.**<sup>58-61</sup>

	2013				
	Global shipments (millions)	Product total W (tons)	Product total Sn (tons)	Product Total Ta (tons)	Product total Au (tons)
Server <sup>60</sup>	9	70	95	19	2
Desktop <sup>61</sup>	130	100	870	57	40
Display <sup>58</sup>	450	400	3240	120	50
Laptop <sup>61</sup>	180	90	360	35	8
Tablet <sup>59</sup>	195	30	170	12	6
Smart phone <sup>58</sup>	910	1040	870	18	14
<b>Total mass for evaluated products (tons)</b>		<b>1730</b>	<b>5600</b>	<b>260</b>	<b>120</b>
Total metal consumption (tons) <sup>45, 50, 54, 55</sup>		95000	359500	1750	4362
<b>Estimated percent of material consumption used by IT</b>		<b>2%</b>	<b>0.1%</b>	<b>15%</b>	<b>3%</b>

<b>products based on global shipments (2013)</b>				
<b>Estimated percent of material consumption used by IT products based on forecasted shipments(2018)</b>	<b>4%</b>	<b>0.3%</b>	<b>27%</b>	<b>5%</b>

342

343 **DISCUSSION**

344 This work developed a model to estimate the amount of tin, tantalum, tungsten, and gold in ICT  
345 products. One limitation of the approach used here stems from the potential for underestimating  
346 the material associated with scrap or chemicals used in the processing and manufacture of  
347 components. To that end, we describe the potential for scrap across 3TG. For tungsten, scrap has  
348 already been considered in the model because every metal layer was estimated to be completely  
349 coated with tungsten rather than what is contained in the vias. Tungsten was estimated using an  
350 “as consumed” approach along with a factor of three to account for wafer yields, edges and other  
351 losses. Communications with the industry have indicated that waste solder paste is between 10  
352 and 20% because the paste used in the solder may adhere to the containers leaving residue in the  
353 cartridges holding the material (personal communication, electronics facility, February 2014).  
354 Typically this tin is not reclaimed, so adding the upper bound of 20% to the tin estimates brings  
355 that total to 1.5% of the total market. Tantalum presents a more challenging estimate as there is  
356 little information about waste in capacitor manufacturing, but communications with the industry  
357 have indicated 92% yield on tantalum in the capacitor manufacturing process. The scrap from  
358 sputtering targets would be larger. Finally, gold waste during production is assumed to be quite  
359 low given the high cost of the material. In addition, targeted recycling of process chemicals and  
360 equipment is widespread such that even if there are inefficiencies the gold would likely be  
361 recovered.

362 Another limitation of the current analysis is that it is not inclusive of all ICT products. In  
363 particular, the analysis excludes devices typically used in ICT enterprise systems such as routers  
364 and switches. Printers were also excluded but can comprise upwards of 10% of the total annual  
365 shipments of IT equipment. However, based on estimations not directly reported here, the total  
366 content of each of the 3TG metals has been estimated to be lower per kg of product for printers  
367 than for the devices examined in this study. For network equipment, we reason that resource  
368 consumption is lower simply because unit volumes are lower. Future work could quantify the  
369 content across a broader range of equipment.

370 Society should be concerned about the potential role of natural resources in funding,  
371 intensifying, and prolonging armed conflict. One tool to diminish that potential is to shift  
372 demand away from resources (or more specifically sources) of concern. To be effective, demand-  
373 based approaches must apply to a large fraction of the market. This study has estimated that  
374 consumer electronics are typically responsible for only a portion of the total use of conflict  
375 minerals (no more than 15% of global consumption for tantalum and 5% for the other 3TG  
376 metals); therefore, to be effective, market pressure must come from multiple sectors. The use of  
377 typical consumer electronic products as examples of conflict minerals in everyday use has been  
378 very successful in highlighting the conflicts that have occurred and continue to occur in DRC.

379 Changes to usage patterns within the electronics sector alone, however, is unlikely to drastically  
380 alter the supply chain economics for these materials.

381 Simple narratives around a single sector create a risk for not fully addressing the problem. For  
382 example, the electronics industry has indicated that it is possible for all consumer electronics to  
383 source their 3TG materials from conflict free regions and steps are underway to do so, including  
384 recent announcements from chipmaker, Intel.<sup>57</sup> There is a risk that concerned stakeholders will  
385 lose their agenda setting influence to motivate other consuming industries once consumer  
386 electronics become “conflict free”. Such an outcome would certainly not be sufficient to address  
387 the underlying problems associated with these resources.<sup>23, 58, 70</sup> While the electronics sector (as  
388 well as relevant metal industry associations) has shown leadership in auditing, validation and  
389 traceability, this has been achieved by a group of approximately 21 companies. Dodd-Frank  
390 affects over 1000 companies and a broader coalition of industries that benefit from the use of  
391 3TG in their products could achieve so much more in terms of creating economic incentives to  
392 generate solutions such as bringing DRC gold into the formal economy and providing  
393 microfinance to former miners who are searching for alternative economic opportunities.<sup>16</sup>

394 Based on the analysis performed in this paper, some relevant policy outcomes are discussed.  
395 Applying economic leverage and pressure within the supply chain is most effective when it is  
396 organized and concentrated. The 3TG topic suffers from low market concentration, as the  
397 potentially most recognizable players (from a consumer perspective) in the sector account for  
398 less than 10% of total industry share. Due to the diluted nature of brand owner influence on  
399 sizeable, consolidated upstream manufacturers when it comes to materials extraction and mining,  
400 the ability to impact and direct the actions of suppliers remains challenging.<sup>71-73</sup> Additionally,  
401 there is an increasing trend of suppliers receiving requests for the same information from  
402 different customers, leading to supplier fatigue. Partnering enables method harmonization and  
403 standardization of the multiple, overlapping survey inquiries on the supply chain. This partnering  
404 should include as broad a representation from the industry as possible so should be extended to  
405 the other uses for each material described above. In general, legislation seems to drive towards  
406 increasing transparency in supply chains that touch materials and chemical industry through  
407 legislation such as Registration, Evaluation, Authorization, and Restriction of Chemicals  
408 (REACH) and Restriction or Use of Hazardous Substances Directive in Electrical and Electronic  
409 Equipment (RoHS). These and other efforts will continue to push understanding of materials  
410 content. Finally, another potential lever that the ICT and other relevant industry sectors can  
411 leverage to influence the impact of metal content in their products would be through increased  
412 recycling, reducing the need for primary extraction at the outset.

## 413 A NOTE ON THE DEFINITION OF CONFLICT MINERALS

414 At the time of the writing of this article, much of the discussion of conflict minerals has been  
415 motivated by impending implementation of relevant sections of the Dodd-Frank Act. As such, at  
416 present, the language of that act has strong influence on the effective definition of the term. As  
417 was noted earlier, the relevant sections of the act define conflict minerals to include cassiterite,  
418 columbite-tantalite, wolframite (the ores from which tin, tantalum, and tungsten are won), and  
419 gold and their derivatives originating from the Democratic Republic of Congo or an adjoining  
420 country. The scope of this list, however, is not necessarily fixed. The act allows for the list to be  
421 expanded to include any mineral or its derivatives determined by the Secretary of State to be

422 financing conflict in the DRC or an adjoining country. Furthermore, while not legally binding,  
423 there are a number of other standards and programs that define conflict minerals even more  
424 broadly. The OECD, for example, has formal guidance for due diligence on the sourcing of these  
425 minerals from “conflict-affected and high-risk” areas throughout the globe.<sup>74</sup> In light of this,  
426 readers are cautioned that the definition of “conflict minerals” may well evolve in the future to a  
427 scope well beyond that covered here.

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## 436 SUPPORTING INFORMATION AVAILABLE

437 This information is available free of charge via the internet at <http://pubs.acs.org/>

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